

FORM PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark Office

Attorney Docket No.: NICHIA-00700

Serial No.: 09/463643

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(37 CFR § 1.98(b))

Applicant: Shuji Nakamura, *et al.*

Filing Date: January 25, 2000

Group Art Unit: 2815

U.S. PATENT DOCUMENTS

Examiner Initials		Serial / Patent Number	Issue Date	Applicant / Patentee	Class	Subclass	Filing Date
BMB	AA	3566215	2/23/71	Heywang	317	235	7/31/68
	AB	3593191	7/13/71	Henker	331	94.5	9/24/69
	AC	3655439	4/11/72	Seiter	117	212	6/16/69
	AD	3658585	4/25/72	Folkmann, <i>et al.</i>	117	201	2/26/70
	AE	3704427	11/28/72	Heywang	331	94.5	6/3/64
	AF	3705567	12/12/72	Emels	118	49	1/22/71
	AG	3737737	6/5/73	Heywang, <i>et al.</i>	317	234.R	10/6/71
	AH	3747559	7/24/73	Dietze	118	48	5/15/72
	AI	3793984	2/26/74	Kasper, <i>et al.</i>	118	48	11/13/72
	AJ	3819974	6/25/74	Stevenson, <i>et al.</i>	313	499	3/12/73
	AK	3853974	12/10/74	Reuschel, <i>et al.</i>	264	81	2/21/73
	AL	3941647	3/2/76	Druminski	156	612	3/8/73
	AM	3948693	4/6/76	Weyrich, <i>et al.</i>	148	171	7/23/74
	AN	3963537	6/15/76	Kniepkamp, <i>et al.</i>	148	175	8/27/74
	AO	3965347	6/22/76	Heywang	250	211.J	11/12/74
	AP	3974561	8/17/76	Schnoeller	29	611	5/30/74
	AQ	4020791	5/3/77	Reuschel, <i>et al.</i>	118	49.1	11/19/74
	AR	4062035	12/6/77	Winstel	357	17	1/28/77
	AS	4098223	7/4/78	Ertl, <i>et al.</i>	118	48	11/4/76
	AT	4102298	7/25/78	Dietze, <i>et al.</i>	118	5	6/10/76
	AU	4108539	8/22/78	Gort, <i>et al.</i>	350	201	11/18/76
	AV	4113381	9/12/78	Epstein	356	5	11/18/76
	AW	4133702	1/9/79	Krimmel	148	1.5	8/11/77
	AX	4140546	2/20/79	Krimmel	148	1.5	8/17/77
	AY	4154625	5/15/79	Golovchenko <i>et al.</i>	148	1.5	11/16/77
	AZ	4170018	10/2/79	Runge	357	17	3/30/78
	BA	4261770	4/14/81	Splittgerber, <i>et al.</i>	148	171	3/13/80
	BB	4351695	9/28/82	Hieber, <i>et al.</i>	156	603	1/2/81
	BC	4404265	9/13/83	Manasevit	428	689	4/7/78
	BD	4410993	10/18/83	Zschauer	372	44	4/17/81
	BE	4423349	12/27/83	Nakajima, <i>et al.</i>	313	487	7/1/81
	BF	4505765	3/19/85	Trommer	148	171	6/17/83
BMB	BG	4521448	6/4/85	Sasaki	427	88	3/3/83

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BH	4531142	7/23/85	Weyrich, <i>et al.</i>	357	17	2/16/83
BI	4568206	2/4/86	Imazaika	384	530	12/3/84
BJ	4596998	6/24/86	Krimmel	357	17	7/19/84
BK	4599244	7/8/86	Falckenberg, <i>et al.</i>	427	74	9/12/84
BL	4599245	7/8/86	Falckenberg, <i>et al.</i>	427	74	9/11/84
BM	4604637	8/5/86	Ruhle, <i>et al.</i>	357	17	3/1/83
BN	4615766	10/7/86	Jackson, <i>et al.</i>	156	662	2/27/85
BO	4656636	4/7/87	Amann, <i>et al.</i>	372	50	12/23/85
BP	4661175	4/28/87	Kuphal, <i>et al.</i>	148	171	6/6/85
BQ	4670093	6/2/87	Macrz, <i>et al.</i>	156	649	4/21/86
BR	4682337	7/21/87	Amann	372	44	9/13/85
BS	4683574	7/28/87	Heinen	372	44	9/12/85
BT	4722088	1/26/88	Wolf	372	44	9/6/85
BU	4740259	4/26/88	Heinen	156	234	9/15/86
BV	4742525	5/3/88	Heinen, <i>et al.</i>	372	44	9/6/85
BW	4744088	5/10/88	Heinen, <i>et al.</i>	372	50	3/13/87
BX	4746195	5/24/88	Auracher, <i>et al.</i>	350	320	3/13/85
BY	4763979	8/16/88	Heywang	350	96.20	9/23/86
BZ	4768199	8/30/88	Heinen, <i>et al.</i>	372	36	9/5/86
CA	4792200	12/20/88	Amann, <i>et al.</i>	350	96.12	4/1/87
CB	4792959	12/20/88	Mueller, <i>et al.</i>	372	46	1/30/87
CC	4818722	4/4/89	Heinen	437	129	5/26/87
CD	4829188	5/9/89	Shinomiya, <i>et al.</i>	250	483.1	10/1/87
CE	4835575	5/30/89	Plihal	357	30	2/3/88
CF	4841344	6/20/89	Heinen	357	17	12/7/87
CG	4845723	7/4/89	Heinen, <i>et al.</i>	372	38	2/22/88
CH	4855118	8/8/89	Ichinose, <i>et al.</i>	423	301	4/12/88
CI	4859903	8/22/89	Minematu, <i>et al.</i>	313	487	3/2/88
CJ	4864369	9/5/89	Snyder, <i>et al.</i>	357	17	7/5/88
CK	4869568	9/26/89	Schimpe	350	96.12	9/29/88
CL	4890033	12/26/89	Ichinomiya, <i>et al.</i>	313	487	6/28/88
CM	4904617	2/27/90	Muschke	437	129	8/25/88
CN	4904618	2/27/90	Neumark	437	150	8/22/88
CO	4907044	3/6/90	Schellhorn, <i>et al.</i>	357	17	7/14/89
CP	4907534	3/13/90	Huang, <i>et al.</i>	118	725	12/9/88
CQ	4911102	3/27/90	Manabe, <i>et al.</i>	118	719	1/26/88

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CR	4918497	4/17/90	Edmond	357	17	12/14/88
CS	4929907	5/29/90	Berkel	330	252	3/8/89
CT	4944837	7/31/90	Nishikawa, <i>et al.</i>	156	646	2/28/89
CU	4945394	7/31/90	Palmour, <i>et al.</i>	357	34	10/26/87
CV	4946547	8/7/90	Palmour, <i>et al.</i>	156	643	10/13/89
CW	4947218	8/7/90	Edmond, <i>et al.</i>	357	13	11/3/87
CX	4959174	9/25/90	Nakajima, <i>et al.</i>	252	301.6R	3/16/89
CY	4960728	10/2/90	Schaake, <i>et al.</i>	437	82	10/11/88
CZ	4966862	10/30/90	Edmond	437	100	8/28/89
DA	4971739	11/20/90	Ichinose, <i>et al.</i>	264	61	4/12/89
DB	4977567	12/11/90	Hanke	372	45	10/11/89
DC	4982314	1/1/91	Miki	363	16	12/4/89
DD	4985742	1/15/91	Pankove	357	34	7/7/89
DE	4987576	1/22/91	Heinen	372	46	11/3/89
DF	4990466	2/5/91	Shieh, <i>et al.</i>	437	129	11/1/88
DG	4990990	2/5/91	Albrecht, <i>et al.</i>	357	30	3/23/88
DH	5005057	4/2/91	Izumiya, <i>et al.</i>	357	17	4/13/90
DI	5006908	4/9/91	Matsuoka, <i>et al.</i>	357	17	2/12/90
DJ	5008735	4/16/91	Edmond, <i>et al.</i>	357	74	12/7/89
DK	5008789	4/16/91	Arai, <i>et al.</i>	362	255	2/14/90
DL	5019746	5/28/91	Merg	313	512	12/4/89
DM	5023686	6/11/91	Helmut, <i>et al.</i>	357	30	6/15/90
DN	5027168	6/25/91	Edmond	357	17	8/28/89
DO	5034956	7/23/91	Gessner, <i>et al.</i>	372	45	11/2/89
DP	5041334	8/20/91	Nakajima, <i>et al.</i>	428	407	12/19/89
DQ	5042043	8/20/91	Hatano, <i>et al.</i>	372	45	4/13/90
DR	5045896	9/3/91	Ash, <i>et al.</i>	357	17	3/21/89
DS	5049779	9/17/91	Itsuki, <i>et al.</i>	313	486	4/28/89
DT	5061972	10/29/91	Edmond	357	13	9/13/90
DU	5065207	11/12/91	Heinen	357	30	2/5/91
DV	5077145	12/31/91	Shinomiya, <i>et al.</i>	428	691	12/21/90
DW	5093576	3/3/92	Edmond, <i>et al.</i>	250	370.01	3/15/91
DX	5119540	6/9/92	Kong, <i>et al.</i>	29	25.01	7/24/90
DY	5120619	6/9/92	Nakajima, <i>et al.</i>	428	690	11/7/90
DZ	5122845	6/16/92	Manabe, <i>et al.</i>	357	17	2/26/90
EA	5128955	7/7/92	Danielmeyer	372	94	8/18/88

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BWB	EB	5146465	9/8/92	Khan, <i>et al.</i>	372	45	2/1/91
	EC	5155062	10/13/92	Coleman	437	100	12/20/90
	ED	5171370	12/15/92	Reithmaier, <i>et al.</i>	118	726	4/18/90
	EE	5182670	1/26/93	Khan, <i>et al.</i>	359	359	8/30/91
	EF	5184247	2/2/93	Schimpe	359	344	7/17/90
	EG	5185207	2/9/93	Furuoka, <i>et al.</i>	428	404	12/27/91
	EH	5200022	4/6/93	Kong, <i>et al.</i>	156	612	10/3/90
	EI	5202777	4/13/93	Sluzky, <i>et al.</i>	359	50	4/1/92
	EJ	5205905	4/27/93	Kotaki, <i>et al.</i>	156	662	5/30/91
	EK	5208878	5/4/93	Thulke	385	14	10/2/91
	EL	5210051	5/11/93	Carter, Jr.	437	107	6/5/91
	EM	5218216	6/8/93	Manabe, <i>et al.</i>	257	103	12/20/91
	EN	5229626	7/20/93	Ebitani, <i>et al.</i>	257	84	3/27/92
	EO	5233204	8/3/93	Fletcher, <i>et al.</i>	257	13	1/10/92
	EP	5239188	8/24/93	Takeuchi, <i>et al.</i>	257	76	11/4/92
	EQ	5247533	9/21/93	Okazaki, <i>et al.</i>	372	45	12/26/91
	ER	5250366	10/5/93	Nakajima, <i>et al.</i>	428	690	5/8/92
	ES	5252499	10/12/93	Rothschild	437	22	8/15/88
	ET	5252839	10/12/93	Fouquet	257	13	6/10/92
	EU	5260960	11/9/93	Amann, <i>et al.</i>	372	46	4/23/92
	EV	5264713	11/23/93	Palmour	257	77	6/14/91
	EW	5266503	11/30/93	Wang, <i>et al.</i>	437	24	10/2/91
	EX	5270554	12/14/93	Palmour	257	77	6/14/91
	EY	5272108	12/21/93	Kozawa	437	127	2/26/92
	EZ	5278433	1/11/94	Manabe, <i>et al.</i>	257	103	8/7/92
	FA	5281830	1/25/94	Kotaki, <i>et al.</i>	257	86	10/24/91
	FB	5290393	3/1/94	Nakamura	156	613	1/28/92
	FC	5306662	4/26/94	Nakamura, <i>et al.</i>	437	107	11/2/92
	FD	5312560	5/17/94	Somatomo, <i>et al.</i>	252	301.4 S	3/18/93
	FE	5323022	6/21/94	Glass, <i>et al.</i>	257	77	9/10/92
	FF	5330791	7/19/94	Aihara, <i>et al.</i>	427	215	4/16/93
	FG	5334277	8/2/94	Nakamura	117	102	10/22/91
	FH	5336080	8/9/94	Sumitomo, <i>et al.</i>	428	407	12/17/92
	FI	5338944	8/16/94	Edmond, <i>et al.</i>	257	76	9/22/93
	FJ	5341390	8/23/94	Yamada, <i>et al.</i>	372	45	4/15/93
BWB	FK	5343316	8/30/94	Morimoto, <i>et al.</i>	359	50	6/29/93

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BWS	FL	5344791	9/6/94	Huang	437	126	8/14/92
	FM	5359345	10/25/94	Hunter	345	102	8/5/92
	FN	5363390	11/8/94	Yang, et al.	372	22	11/22/93
	FO	5366834	11/22/94	Yoneda, et al.	430	23	5/5/93
	FP	5369289	11/29/94	Tamaki, et al.	257	99	10/30/92
	FQ	5376303	12/27/94	Royce, et al.	252	301.4 R	1/10/94
	FR	5376580	12/27/94	Kish, et al.	437	127	3/19/93
	FS	5381103	1/10/95	Edmond, et al.	324	753	10/13/92
	FT	5382822	1/17/95	Stein	257	410	9/27/93
	FU	5389571	2/14/95	Takeuchi, et al.	437	133	4/16/93
	FV	5390210	2/14/95	Fouquet, et al.	372	92	11/22/93
	FW	5393993	2/28/95	Edmond, et al.	257	77	12/13/93
	FX	5394005	2/28/95	Brown, et al.	257	461	2/18/94
	FY	5403774	4/4/95	Shieh, et al.	437	129	11/6/92
	FZ	5404282	4/4/95	Klinke, et al.	362	249	8/19/94
	GA	5408120	4/18/95	Manabe, et al.	257	431	1/22/93
	GB	5409859	4/25/95	Glass, et al.	437	187	4/22/94
	GC	5416342	5/16/95	Edmond, et al.	257	76	6/23/93
	GD	5417886	5/23/95	Tateiwa, et al.	252	301.4 R	9/20/93
	GE	5433169	7/18/95	Nakamura	117	102	4/6/94
	GF	5433533	7/18/95	Imazaike	384	488	12/20/93
	GG	5433888	7/18/95	Okada, et al.	252	301.4 R	9/20/93
	GH	5435938	7/25/95	Bando, et al.	252	301.4 S	3/10/94
	GI	5438198	8/1/95	Ebitani, et al.	250	330	5/3/94
	GJ	5459107	10/17/95	Palmour	437	238	6/5/92
	GK	5465249	11/7/95	Cooper, Jr. et al.	365	149	11/26/91
	GL	5467291	11/14/95	Fan, et al.	364	578	12/5/91
	GM	5468678	11/21/95	Nakamura, et al.	437	107	1/12/94
	GN	5475241	12/12/95	Harrah, et al.	257	99	10/27/93
	GO	5497012	3/3/96	Moll	257	183	6/15/94
	GP	5502316	3/26/96	Kish, et al.	257	94	10/12/95
	GQ	5506421	4/9/96	Palmour	257	77	11/24/92
	GR	5511084	4/23/96	Amann	372	20	1/17/95
	GS	5514627	5/7/96	Lowery, et al.	437	209	1/24/94
	GT	5523018	6/4/96	Okada, et al.	252	301.4 P	3/23/95
BWB	GU	5523589	6/4/96	Edmond, et al.	257	77	9/20/94

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GV	5539217	7/23/96	Edmond, et al.	257	77	8/9/93
GW	5563422	10/8/96	Nakamura, et al.	257	13	4/28/94
GX	5578839	11/26/96	Nakamura, et al.	257	96	11/17/93
GY	5583879	12/10/96	Yamazaki, et al.	372	45	4/19/95
GZ	5585648	12/17/96	Tischler	257	77	2/3/95
HA	5587593	12/24/96	Koide, et al.	257	94	4/19/95
HB	5592501	1/7/97	Edmond, et al.	372	45	9/20/94
HC	5592578	1/7/97	Ruh	385	31	11/1/95
HD	5596595	1/21/97	Tan, et al.	372	96	6/8/95
HE	5604135	2/18/97	Edmond, et al.	437	22	8/12/94
HF	5604763	2/18/97	Kato, et al.	372	45	4/19/95
HG	5612260	3/18/97	Palmour	437	238	12/9/94
HH	5614736	3/25/97	Neumann, et al.	257	102	9/25/95
HI	5616177	4/1/97	Yamada	117	102	2/22/95
HJ	5620557	4/15/97	Manabe, et al.	438	507	6/26/95
HK	5621749	4/15/97	Baney	372	69	9/6/95
HL	5625202	4/29/97	Chai	257	94	6/8/95
HM	5627244	5/6/97	Sato	526	92	4/26/95
HN	5629531	5/13/97	Palmour	257	77	12/9/94
HO	5631190	5/20/97	Negley	438	33	10/7/94
HP	5635146	6/3/97	Singh, et al.	423	65	11/30/95
HQ	5642375	6/24/97	King, et al.	372	97	10/26/95
HR	5650641	7/22/97	Sassa, et al.	257	88	8/31/95
HS	5652434	7/29/97	Nakamura, et al.	257	13	6/17/96
HT	5652438	7/29/97	Sassa, et al.	257	94	7/19/95
HU	5656832	8/12/97	Ohba, et al.	257	190	3/8/95
HV	5659568	8/19/97	Wang, et al.	372	96	5/23/95
HW	5661074	8/26/97	Tischler	438	32	5/24/95
HX	5661316	8/26/97	Kish, Jr., et al.	257	190	9/20/96
HY	5661742	8/26/97	Huang, et al.	372	46	5/22/96
HZ	5670798	9/23/97	Schetzina	257	96	3/29/95
IA	5679153	10/21/97	Dmitriev, et al.	117	106	11/30/94
IB	5684623	11/4/97	King, et al.	359	346	11/21/96
IC	5686737	11/11/97	Allen	257	77	9/16/94
ID	5700713	12/23/97	Yamazaki, et al.	437	129	3/20/95
IE	5707139	1/13/98	Haitz	362	231	11/1/95

Examiner: *B. H. Brown*

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IF	5718760	2/17/98	Carter, <i>et al.</i>	117	84	2/5/96
IG	5719409	2/17/98	Singh, <i>et al.</i>	257	77	6/6/96
IH	5724062	3/3/98	Hunter	345	102	9/21/94
II	5724373	3/3/98	Chang	372	20	11/15/96
IJ	5724376	3/3/98	Kish, Jr., <i>et al.</i>	372	96	11/30/95
IK	5727014	3/10/98	Wang, <i>et al.</i>	372	96	10/31/95
IL	5729029	3/17/98	Rudaz	257	13	9/6/96
IM	5729567	3/17/98	Nakagawa	372	99	4/25/96
IN	5733796	3/31/98	Manabe, <i>et al.</i>	437	127	11/9/95
IO	5734182	3/31/98	Nakamura, <i>et al.</i>	257	96	6/10/96
IP	5739552	4/14/98	Kimura, <i>et al.</i>	257	89	10/24/95
IQ	5739554	4/14/98	Edmond, <i>et al.</i>	257	103	5/8/95
IR	5741431	4/21/98	Shih	216	65	5/15/97
IS	5741724	4/21/98	Ramdani, <i>et al.</i>	437	128	12/27/96
IT	5742133	4/21/98	Wilhelm, <i>et al.</i>	315	291	9/9/96
IU	5747832	5/5/98	Nakamura, <i>et al.</i>	257	103	6/10/96
IV	5753939	5/19/98	Sassa, <i>et al.</i>	257	94	3/7/97
IW	5758951	6/2/98	Haitz	362	259	6/27/97
IX	5761229	6/2/98	Baldwin, <i>et al.</i>	372	31	1/25/96
IY	5767581	6/16/98	Nakamura, <i>et al.</i>	257	749	6/17/96
IZ	5771254	6/23/98	Baldwin, <i>et al.</i>	372	31	6/3/96
JA	5776837	7/7/98	Palmour	438	767	11/19/96
JB	5777350	7/7/98	Nakamura, <i>et al.</i>	257	96	11/30/95
JC	5777433	7/7/98	Lester, <i>et al.</i>	313	512	7/11/96
JD	5779924	7/14/98	Krames, <i>et al.</i>	216	24	3/22/96
JE	5780120	7/14/98	Belouet, <i>et al.</i>	427	554	12/18/96
JF	5785404	7/28/98	Wiese	362	32	6/29/95
JG	5793054	8/11/98	Nido	257	18	6/13/96
JH	5793062	8/11/98	Kish, Jr., <i>et al.</i>	257	98	10/24/97
JI	5805624	9/8/98	Yang, <i>et al.</i>	372	45	7/30/96
JJ	5808323	9/15/98	Spaeth, <i>et al.</i>	257	88	3/29/96
JK	5808592	9/15/98	Mizutani, <i>et al.</i>	345	83	4/21/95
JL	5809050	9/15/98	Baldwin, <i>et al.</i>	372	43	1/25/96
JM	5811319	9/22/98	Koike, <i>et al.</i>	438	46	3/26/96
JN	5811931	9/22/98	Mueller-Mach, <i>et al.</i>	313	512	3/4/96
JO	5812105	9/22/98	Van De Ven	345	83	6/10/96

Examiner: *B. M. Brown*

Date Considered: 9/15/01

EXAMINER:

Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark Office

Attorney Docket No.: NICHIA-00700

Serial No.: 09/463643

Applicant: Shuji Nakamura, *et al.*

Filing Date: January 25, 2000

Group Art Unit: 2815

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(37 CFR § 1.98(b))

BWB	JP	5812570	9/22/98	Spaeth	372	36	9/30/96
	JQ	5814870	9/29/98	Spaeth	257	433	1/6/97
	JR	5818861	10/6/98	Tan, <i>et al.</i>	372	46	7/19/96
	JS	5828684	10/27/98	Van De Walle	372	45	12/29/95
	JT	5831288	11/3/98	Singh, <i>et al.</i>	257	77	9/29/97
	JU	5835514	11/10/98	Yuen, <i>et al.</i>	372	36	1/25/96
	JV	5835522	11/10/98	King, <i>et al.</i>	372	97	11/19/96
	JW	5837561	11/17/98	Kish, Jr., <i>et al.</i>	438	47	5/23/97
	JX	5838706	11/17/98	Edmond, <i>et al.</i>	372	45	11/19/96
	JY	5838707	11/17/98	Ramdani, <i>et al.</i>	372	45	12/27/96
	JZ	5838708	11/17/98	Lin, <i>et al.</i>	372	50	8/1/95
	KA	5846844	12/8/98	Akasaki, <i>et al.</i>	437	21	2/7/96
	KB	5847507	12/8/98	Butterworth, <i>et al.</i>	313	512	7/14/97
	KC	5850410	12/15/98	Kuramata	372	43	3/18/96
	KD	5855924	1/5/99	Lumbard	425	116	12/27/95
	KE	5858277	1/12/99	Chau, <i>et al.</i>	252	301.4 F	12/23/92
	KF	5859496	1/12/99	Murazaki, <i>et al.</i>	313	485	5/10/96
	KG	5861190	1/19/99	Greene, <i>et al.</i>	427	248.1	3/25/96
	KH	5861713	1/19/99	Kondo, <i>et al.</i>	313	495	6/26/97
	KI	5862167	1/19/99	Sassa, <i>et al.</i>	372	45	5/27/97
	KJ	5867516	2/2/99	Corzine, <i>et al.</i>	372	45	3/12/96
	KK	5868837	2/9/99	Disalvo, <i>et al.</i>	117	952	1/13/98
	KL	5877558	3/2/99	Nakamura, <i>et al.</i>	257	749	12/19/97
	KM	5879587	3/9/99	Yale	252	301.45	9/24/97
	KN	5879588	3/9/99	Yale	252	301.45	9/24/97
	KO	5880486	3/9/99	Nakamura, <i>et al.</i>	257	96	8/30/96
	KP	5889802	3/30/99	Walker	372	31	3/27/97
	RQ	5889806	3/30/99	Nagai, <i>et al.</i>	372	45	8/8/97
	KR	5892784	4/6/99	Tan, <i>et al.</i>	372	43	10/27/94
	KS	5892787	4/6/99	Tan, <i>et al.</i>	372	96	4/22/96
	RT	5900650	5/4/99	Nitta	257	94	7/2/97
	KU	5905276	5/18/99	Manabe, <i>et al.</i>	257	103	11/6/97
	KV	5907151	5/25/99	Gramann, <i>et al.</i>	250	214.1	5/27/97
	KW	5912477	6/15/99	Negley	257	95	5/20/97
	KX	5917202	6/29/99	Haitz, <i>et al.</i>	257	98	12/21/95
BWB	KY	5919422	7/6/99	Yamanaka, <i>et al.</i>	422	121	7/26/96

Examiner: *BWB*

Date Considered: 9/15/01

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Attorney Docket No.: NICHIA-00700

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(37 CFR § 1.98(b))

Applicant: Shuji Nakamura, *et al.*

Filing Date: January 25, 2000

Group Art Unit: 2815

BWB	KZ	5920766	7/6/99	Floyd	438	35	1/7/98
	LA	5923053	7/13/99	Jakowetz, <i>et al.</i>	257	95	9/30/96
	LB	5923118	6/13/99	Jennato, <i>et al.</i>	313	485	3/7/97
	LC	5923690	7/13/99	Kume, <i>et al.</i>	372	46	1/24/97
	LD	5923946	7/13/99	Negley	438	4	4/17/97
	LE	5925898	7/20/99	Spath	257	98	1/26/98
	LF	5927995	7/27/99	Chen, <i>et al.</i>	438	517	4/9/97
	LG	5935705	8/10/99	Chen, <i>et al.</i>	428	367	10/15/97
	LH	5936985	8/10/99	Yamamoto, <i>et al.</i>	372	38	9/13/95
	LI	5945689	8/31/99	Koike, <i>et al.</i>	257	88	3/18/96
	LJ	5953361	9/14/99	Borchert, <i>et al.</i>	372	96	11/25/97
	LK	5953581	9/14/99	Yamasaki, <i>et al.</i>	438	22	4/17/97
	LL	5958295	9/28/99	Yale	252	301.4 S	9/24/97
	LM	5959316	9/28/99	Lowery	257	98	9/1/98
	LN	5959401	9/28/99	Asami, <i>et al.</i>	313	503	5/21/97
	LO	5961723	10/5/99	Roithner, <i>et al.</i>	118	715	11/26/96
	LP	5964943	10/12/99	Stein, <i>et al.</i>	117	88	6/25/97
	LQ	5966393	10/12/99	Hide, <i>et al.</i>	372	23	2/4/97
	LR	5968265	10/19/99	Stein, <i>et al.</i>	117	71	1/27/98
	LS	5969378	10/19/99	Singh	257	77	7/10/97
	LT	5972781	10/26/99	Wegleiter, <i>et al.</i>	438	460	9/30/97
	LU	5972801	10/26/99	Lipkin, <i>et al.</i>	438	770	11/8/95
	LV	5973336	10/26/99	Hanke, <i>et al.</i>	257	94	11/3/97
	LW	5980631	11/9/99	Tews, <i>et al.</i>	117	89	12/17/97
	LX	5981945	11/9/99	Spaeth, <i>et al.</i>	250	239	3/8/96
	LY	5981979	11/9/99	Brunner	257	99	11/26/97
	LZ	5982970	11/9/99	Schneider	385	125	9/19/97
	MA	5986317	11/16/99	Wiese	257	433	9/29/95
	MB	5991160	11/23/99	Lumbard	361	760	12/27/95
	MC	5994722	11/30/99	Averbeck, <i>et al.</i>	257	89	6/30/98
	MD	5998925	12/7/99	Shimizu, <i>et al.</i>	313	503	7/29/97
	ME	5999552	12/7/99	Bogner, <i>et al.</i>	372	43	1/20/98

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	MF	Document Number	Publication Date	Country / Patent Office	Class	Subclass	Translation
	MG	CA1325582	12/28/93	CA	HO1L	21/36B	
BWB	MH	EP0356059A2	2/28/90	EP	HO1L	21/38	

Examiner: B. H. Brown

Date Considered: 2/15/01

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FORM PTO-1449
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U.S. Department of Commerce
Patent and Trademark Office

Attorney Docket No.: NICHIA-00700

Serial No.: 09/463643

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(37 CFR § 1.98(b))

Applicant: Shuji Nakamura, et al.

Filing Date: January 25, 2000

Group Art Unit: 2815

BWB	MI	EP0356059A3	2/28/90	EP	HOIL	21/38	
	MJ	EP0380340A2	8/1/90	EP	HOIL	29/91	
	MK	EP0380340A3	8/1/90	EP	HOIL	29/91	
	ML	EP0637069A1	2/1/95	EP	HOIL	21/473	
	MM	EP0731512A2	9/11/96	EP	HOIL	33/00	
	MN	EP0731512A3	7/2/97	EP	HOIL	33/00	
	MO	EP0781619A1	7/2/97	EP	B23H	7/02	
	MP	EP0871208A2	10/14/98	EP	HOIL	21/20	
	MQ	EP0871208A3	12/16/98	EP	HOIL	21/20	
	MR	EP0880181A2	11/25/98	EP	HOIL	29/45	
	MS	EP0880181A3	1/20/99	EP	HOIL	29/45	
	MT	EP0905799A2	3/31/99	EP	HOIL	33/00	
	MU	EP0936682A1	8/18/99	EP	HOIL	33/00	
	MV	FR2613136	9/30/88	FR	HOIL	33/00	
	MW	GB2322737A	3/2/98	GB	HOIL	21/304	
	MX	GB2323210A	9/16/98	GB	HOIL	33/00	
	MY	JP05152609	6/18/93	JP	HOIL	33/00	
BWB	MZ	JP0766192	3/10/95	JP	HOIL	29/78	
	NA	JP09193137	7/29/97	JP	B28D	5/044	
	NB	JP10233529	2/14/97	JP	HOIL	33/00	
BWB	NC	JP1064854	7/18/96	JP	HOIL	21/301	
	ND	JP7176794	7/14/95	JP	HOIL	33/00	
	NE	WO9702478A1	1/23/97	PCT	G01M	19/00	
	NE	WO9702610A1	1/23/97	PCT	HOIL	31/173	
	NG	WO9717730A1	5/15/97	PCT	HOIL	29/24	
	NH	WO9727629A1	7/31/97	PCT	HOIL	29/06	
	NI	WO9739485A1	10/23/97	PCT	HOIL	2706	
	NJ	WO9750132A1	12/31/97	PCT	HOIL	33/00	
	NK	WO9805078A1	2/5/98	PCT	HOIL	33/00	
	NL	WO9812757A1	3/26/98	PCT	HOIL	33/00	
	NM	WO9834304A1	8/6/98	PCT	HOIS	3/025	
	NN	WO9837586A1	8/27/98	PCT	HOIL	33/00	
	NO	WO9842879A1	10/1/98	PCT	C21C	5/35	
	NP	WO9842897A1	10/1/98	PCT	C30B	25/12	
	NQ	WO9847185A1	10/22/98	PCT	HOIL	33/00	
BWB	NR	WO9849731A1	11/5/98	PCT	HOIL	29/739	

Examiner: *Mr. Bann*

Date Considered: 9/15/01

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Sheet 11 of 11			
FORM PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney Docket No.: NICHIA-00700	Serial No.:09/463643
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR § 1.98(b))		Applicant: Shuji Nakamura, <i>et al.</i>	
		Filing Date: January 25, 2000	Group Art Unit: 2818

BNI	NS	WO9857378A1	12/17/98	PCT	HOIL	29/73	
	NT	WO9910936A2	3/4/99	PCT	HOIL	33/00	
	NU	WO9910936A3	3/4/99	PCT	HOIL	33/00	
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	OA	"Effects of Ar Ion Laser Irradiation on MOVPE of ZnSe using DMZn and DMSe as Reactants," A. Yoshikawa, Journal of Crystal Growth, pp.653-658, 1991.
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	OC	"High Quality GaN Grown Directly on SiC by Halide Vapour Phase Epitaxy," Y.V. Melnik, Inst. Phys. Conf., pp.863-866, 1996.
	OD	"Luminescence Conversion of Blue Light Emitting Diodes," P. Schlotter, Journal of Applied Physics, pp.12-13, 2/27/97.
	OE	"P-Type Conduction in Mg-Doped GaN Treated with Low-Energy Electron Beam Irradiation (LEEBI)," H. Amano, Japanese Journal of Applied Physics, pp.2112-2114, 12/89.
	OF	"Photoluminescence of Mg-Doped P-Type GaN and Electroluminescence of GaN P-N Junction Led," I. Akasaki, Journal of Luminescence Vol. 48-49, pp.666-670, 1991.
	OG	"Recent Progress in AlGaIn/GaN Laser Structures on 6H-SiC," G.E. Bulman, SPIE Vol. 2693, pp.57-63, 1996.
	OH	"Recent Progress in GaN/SiC LEDs and Photopumped Lasers," G.E. Bulman, pp.100-101, 19xx.
	OI	"Role of Growth Initiation for High-Brightness GaN-Based Light Emitting Diodes," R.S. Kern, 2nd. Intern. Symp. on Blue Laser and Light Emitting Diodes, Chiba, Japan, 9/29-10/2/98.
	OJ	"The State of SiC: GaN-Based Blue LEDs," J. Edmond, Inst. Phys. Conf. Ser. No. 142, Chap. 6, pp.991-994, 1996.
	OK	"Wide Bandgap Group-III Nitride Optoelectronics," http://www.phy.duke.edu/research/photon/terahertz/gan/index.html .
BNI	OL	"White LED Production at Osram," G. Bogner, Compound Semiconductor, pp.28-31, 5/99.

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Examiner: <i>[Signature]</i>	Date Considered: 9/15/01
EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

INFORMATION DISCLOSURE
CITATION

ATTY. DOCKET NO.

925-178

APPLICANT

NAKAMURA et al

FILING DATE

May 1, 2000

SERIAL NO.

09/463,643

GROUP

2815

(Use several sheets if necessary)



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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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								YES	NO
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		X	03-252175	11/1991	Japan			ABS	
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		X	06-151965	5/1994	Japan			ABS	
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		X	08-056015	2/1996	Japan			ABS	
		X	08-070139	3/1996	Japan			ABS	
		X	08-116090	5/1996	Japan			ABS	
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		X	10-41549	2/1998	Japan				X

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*Examiner

Date Considered

7/11/03

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

#15 / 100
4-2-02
R. Duke

SERIAL NO.

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925-178 ..

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U.S. PATENT DOCUMENTS

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DOCUMENT		DATE	COUNTRY	CLASS	SUBCLASS	YES	NO	
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BWB	61221726	10/1986	Japan			abs		
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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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*Examiner

Date Considered

5/30/02

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

Serial No. 09/463643

Group Art Unit:

28/5

Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark Office

Attorney Docket No.: NICHIA-00700

Serial No.: 09/463,643

• INFORMATION DISCLOSURE STATEMENT BY APPLICANT
(Use Several Sheets If Necessary)

(37 CFR § 1.98(b))

Applicant: Shuji Nakamura *et al.*

Filing Date: January 25, 2000

Group Art Unit: 2815

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		Document Number	Publication Date	Country / Patent Office	Class	Subclass	Translation	
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Examiner: *B. M. B...*

Date Considered: 9/15/01

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